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Docket Number (Optional)	Application Number
P 6079.11005	09/837,887
Applicant(s)	
Voorakaranam et al.	
Filing Date	**Group Art Unit**
April 18, 2001	~~2858~~ 2857

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
RW		6,114,858	9/5/00	Kasten	324	616	

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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES	Translation NO

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Kol Wahnn	9-15-04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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